# FQP2N90

### 900V N-Channel MOSFET

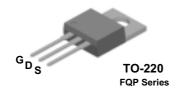
## **General Description**

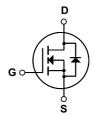
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supply.

#### **Features**

- 2.2A, 900V,  $R_{DS(on)}$  = 7.2  $\Omega$  @  $V_{GS}$  = 10 V Low gate charge ( typical 12 nC)
- Low Crss (typical 5.5 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQP2N90	Units
V <sub>DSS</sub>	Drain-Source Voltage		900	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		2.2	А
	- Continuous (T <sub>C</sub> = 100°C	<b>(</b> )	1.39	А
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	8.8	А
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	170	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	2.2	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	8.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.0	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		85	W
	- Derate above 25°C		0.68	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.47	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	900			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 2	5°C	1.0		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 900 V, V <sub>GS</sub> = 0 V			10	μΑ
		V <sub>DS</sub> = 720 V, T <sub>C</sub> = 125°C			100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	aracteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1.1 A		5.6	7.2	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 1.1 A (No	te 4)	2.0		S
C <sub>oss</sub> C <sub>rss</sub>	Output Capacitance Reverse Transfer Capacitance	f = 1.0 MHz		45 5.5	7.0	pF pF
133	Torsion Hallow Capacitation			0.0		ρ.
	ing Characteristics	T		T	Т	
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 450 V, I <sub>D</sub> = 2.2 A,		15	40	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		35	80	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	(Note		20	50	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note	4, 5)	30	70	ns
$Q_g$	Total Gate Charge	$V_{DS} = 720 \text{ V}, I_{D} = 2.2 \text{ A},$		12	15	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = 10 V		2.8		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note	4, 5)	6.1		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				2.2	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				8.8	Α
		\\			1.4	V
	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.2 \text{ A}$			1.4	V
V <sub>SD</sub>	Drain-Source Diode Forward Voltage Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 2.2 \text{ A}$ $V_{GS} = 0 \text{ V}, I_S = 2.2 \text{ A},$		400		ns

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 65mH, I<sub>AS</sub> = 2.2A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  2.2A, di/dt  $\leq$  200A/μs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

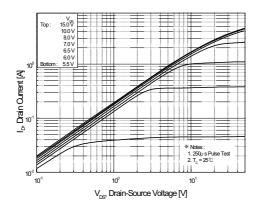


Figure 1. On-Region Characteristics

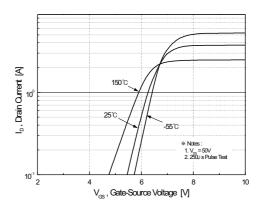


Figure 2. Transfer Characteristics

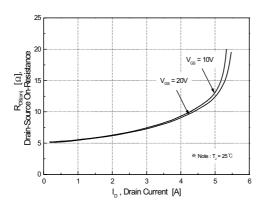


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

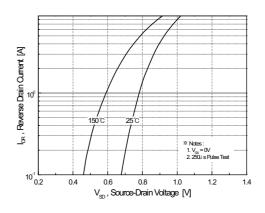


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

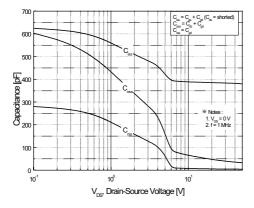


Figure 5. Capacitance Characteristics

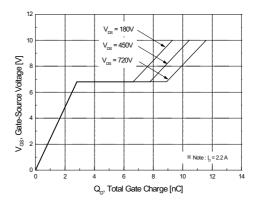


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)

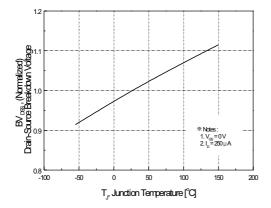


Figure 7. Breakdown Voltage Variation vs. Temperature

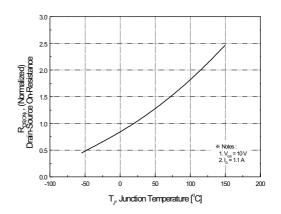


Figure 8. On-Resistance Variation vs. Temperature

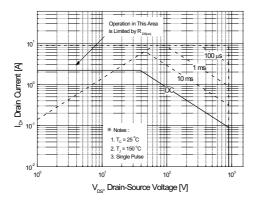


Figure 9. Maximum Safe Operating Area

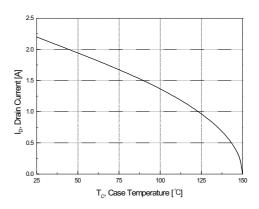


Figure 10. Maximum Drain Current vs. Case Temperature

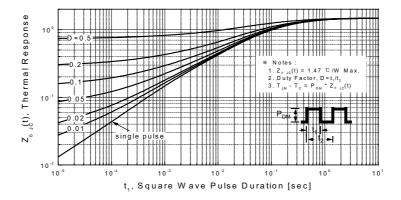
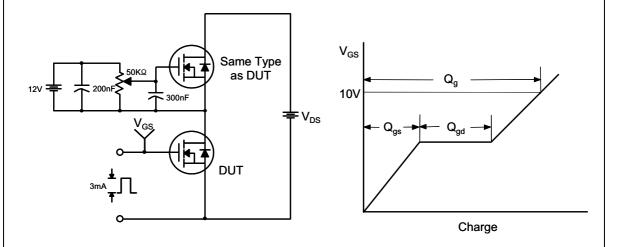


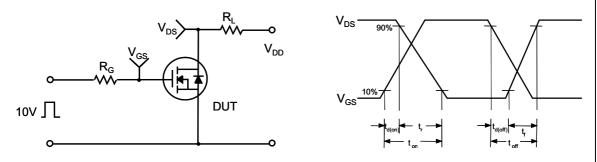
Figure 11. Transient Thermal Response Curve

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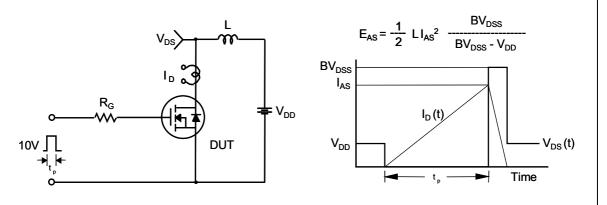
# **Gate Charge Test Circuit & Waveform**



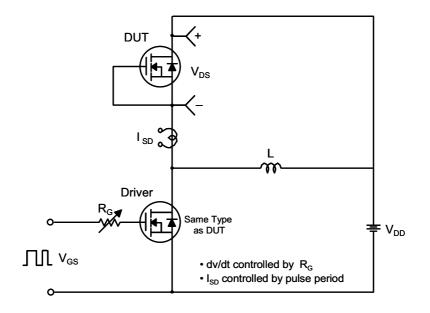
# **Resistive Switching Test Circuit & Waveforms**

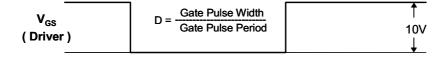


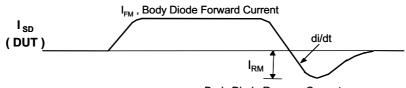
# **Unclamped Inductive Switching Test Circuit & Waveforms**



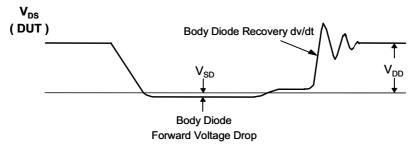
### Peak Diode Recovery dv/dt Test Circuit & Waveforms

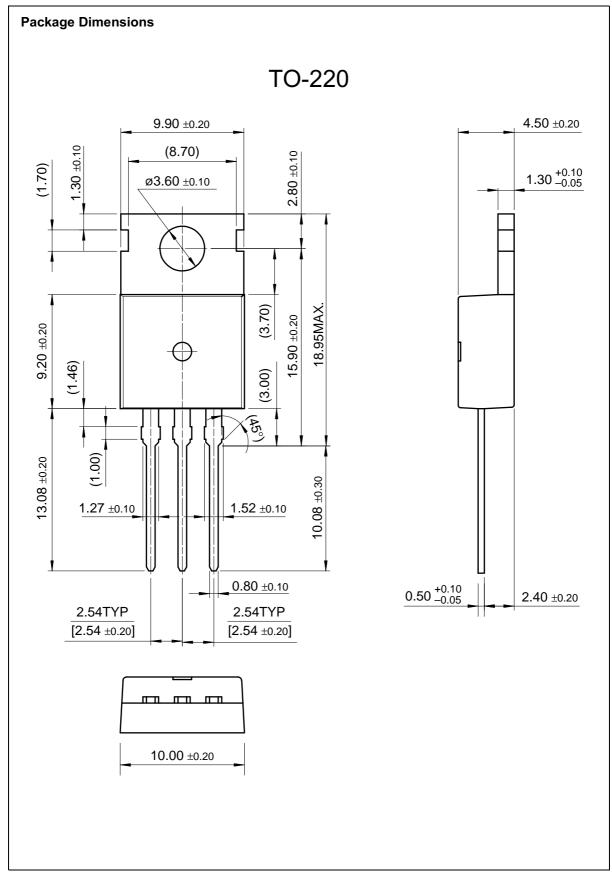






Body Diode Reverse Current





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